Inventor Information

Inventor One Given Name:

Family Name: Name Suffix:

Postal Address Line One Postal Address Line Two

City:

State or Province: Postal or Zip Code: Citizenship Country:

Inventor Two Given Name:

Family Name: Name Suffix:

Postal Address Line One Postal Address Line Two

City:

State or Province:
Postal or Zip Code:
Citizenship Country:

Inventor Three Given Name:

Family Name: Name Suffix:

Postal Address Line One Postal Address Line Two

Citv:

State or Province: Postal or Zip Code: Citizenship Country:

Inventor Four Given Name:

Family Name: Name Suffix:

Postal Address Line One Postal Address Line Two

City:

State or Province: Postal or Zip Code: Citizenship Country: Akihiko ITO

5-2-35-201, Higashi

Hanyu-shi Saitama Japan 348-0052 Japan

Yoshihito KOBAYASHI

1-11-6, Sakuracho

Gyoda-shi Saitama Japan 361-0022 Japan

Yoshiyuki MASUO

4-5-405, Shimizucho

Gyoda-shi Saitama Japan 361-0047 Japan

Tsuyoshi YAMASHITA

4911-A-201, Nakano

Oramachi

Ora-gun, Gunma

Japan 370-0603 Japan

Correspondence Information

Name Line One:

Name Line Two: Morrison & Foerster LLP

Address Line One: 425 Market Street

Address Line Two:

City: San Francisco

State or Province: California
Postal or Zip Code: 94105-2482

Telephone: (415) 268-6147 Fax: (415) 268-7522

Electronic Mail: Kapouytian@mofo.com

Application Information

Title Line One: SEMICONDUCTOR DEVICE TESTING APPARATUS AND A TEST TRAY FOR

Ararat Kapouytian

Title Line Two:

Title Line Three:

APPARATUS AND A TEST TRAT FOR USE IN THE TESTING APPARATUS

Total Drawing Sheets: Fourteen (14)

Formal Drawings?: Yes
Application Type: Utility

Docket Number: 333772000101

Representative Information

Representative Customer Number: 20872

Continuity Information

This application is a: > Application One:

Filing Date:

Continuation of 09/254,084

February 26, 1999

which is a:

>>Application Two:

Filing Date:

which is a:

>>>Application Three:

Filing Date:

Prior Foreign Applications

Foreign Application One: Filing Date:

Country: Priority Claimed:

PCT/JP98/02979 July 2, 1998

Japan yes